EXAMINER	V 'S	rwija	DATE CONSIDERED	17/09			
	1	hanla	01	halai.			
				· · · · · · · · · · · · · · · · · · ·			
		OTHER DOCUME	NT(S) (Including Author, Title, Date, Pertinent Pages,	, Etc.)			
	NUMBER					OR ABSTRACT	
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS		
			FOREIGN PATENT DOCUMENTS				
				10011			
			·		Technology Center 2600		
					FEB 1 1 2004		
				R	ECEIV	/FD	
				-			
V/   -	6,229,601	08/2001	Hasegawa	356	141.5		
INITIAL			NAME	CLASS		IF APPROPRIATE	
*EXAMINER	DOCUMENT	TO TRACE MICE		31.45		FILING DATE	
		FEB 0 4 2004 657	U.S. PATENT DOCUMENTS				
Submitted to the PTO: February 4, 2004				GROUP <b>2673</b>			
LIST OF R	TENT AND TRADEMAF EFERENCES CITED B Use several sheets if ne	BY ABPLICANTISM	APPLICANTS ATSUSHI TANAKA, ET AL.	· · · · · · · · · · · · · · · · · · ·			
FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE			00862.021861		APPLICATION NO. 09/526,463		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SDM\mm DC\_MAIN 155824v1 Sheet\_1\_ of \_1\_